Brammer Standard Company, Inc.

Certificate of Analysis

REVISION OF BS 192

Certified Reference Material¹ for 17-7PH Stainless Steel Alloy (UNS Number \$17700)

	Certified Value ²	Estimate of Uncertainty ³	Certified Value ²	Estimate of Ucertainty ³	
		Analysis listed	d as percent by weight		
С	0.074	0.002	0	0.0014	0.0003
Mn	0.835	0.008	Nb	0.168	0.006
Р	0.025	0.001	Sn	0.008	0.001
s	0.0005	0.00015	Ti	0.076	0.004
Si	0.387	0.010	V	0.124	0.003
Cu	0.412	0.007	w	0.05	0.01
Ni	7.11	0.05			
Cr	16.44	0.06			
Мо	0.430	0.010			
Al	1.17	0.015	Informatio	n Values ⁴	
Са	0.0007	0.0002	As	0.005	
Co	0.104	0.004	В	0.0003	
N	0.0290	0.0008	Та	0.001	

¹ Brammer Standard Company, Inc., is accredited to ISO Guide 34 as a Reference Material Producer to produce Certified Reference Materials by A2LA (Certificate Number 656.02)

See the following pages for more information.

Certificate Number 192REV-032901p1

² The certified value listed is the present best estimate of the true value based on the results of an interlaboratory testing program.

³ The uncertainties listed are based on value judgments of the material inhomogeneity and the 95% confidence interval. The half-width confidence interval C(95%) is shown on page 2.

⁴ Information values are not certified and are provided for information only.

BS 192REV	REV Data listed as mass fraction expressed as percent. 192REV-032901p2																	
Analysis	*	C	*	Mn	*	P	*	S	*	Si	*	Cu	*	Ni	*	Cr	*	Mo
1 2 3 4 5 6 7 8 9 10 11 12 13 14 15 16 17 18		C 0.07 AES 0.07 AES 0.07	2 26 3 3 3 3 4 4 4 4 4 4 4 4 6 5 6 6 8 7	AA 0.81 MnP 0.82 AIC 0.82 AES 0.82 AIC 0.82 AES 0.83 AIC 0.83 AIC 0.83 XRF 0.83 XRF 0.84 AIC 0.84 AIC 0.84 AIC 0.84 AIC 0.84 AAC 0.84 AAC 0.85	9 4 5 7 7 4 8 9 0 5 7 8 0 0 3 5 6 6 0	AIC 0.02 AGA 0.02 AIC 0.02 AIC 0.02 AIC 0.02 XRF 0.02 AIC 0.02 XRF 0.02 AIC 0.02	333 337 4 41 443 445 55 55 55 66 72 84	C 0.00 C 0.00 C 0.00 C 0.00 C 0.00 C 0.00 C 0.00 C 0.00	02 02 03 042 05 06 06 07	AIC 0.35 XRF 0.36 AES 0.37 AIC 0.38 AIC 0.38 AIC 0.38 AIC 0.38 AGS 0.38 AGG 0.39 GG 0.39 GG 0.39 GG 0.39	59 58 75 31 32 33 36 36 36 36 36 36 36 36 36 36 36 36	AIC 0.39 XRF 0.40 AGX 0.40 AIC 0.40 AIC 0.41 ECS 0.41 MCT 0.41 MCB 0.41 XRF 0.41 XRF 0.41 AIC 0.41 AES 0.42 AIC 0.42 AIC 0.42	5 2 6 8 9 0 0 1 2 2 4 5 6 0 2 4	XRF 7.07 AIC 7.07 AES 7.07 TN1 7.07 TN1 7.07 AIC 7.08 XRF 7.09 GN1 7.10 AES 7.10 GN1 7.11 AIC 7.12 TN1 7.13 AGA 7.14 AIC 7.14 AIC 7.14	5 7 9	AES 16.3 AIC 16.3 TCr 16.3 XRF 16.3 XRF 16.3 AES 16.4 XRF 16.4 XRF 16.4 TCr 16.4 AIC 16.4 TCr 16.4 TCr 16.4 TCr 16.4 TCr 16.4 TCr 16.4	7 7 8 8 9 9 5 0 1 2 3 3 4 4 6 7 7 8 65 7	AES 0.410 AIC 0.415 AES 0.418 AIC 0.422 AA 0.423 XRF 0.424 AIC 0.424 AIC 0.430 GMo 0.432 AIC 0.433 AIC 0.433 AIC 0.433 AIC 0.433 AIC 0.435 AIC 0.436 AIC 0.436 AIC 0.436 AIC 0.436 AIC 0.436 AIC 0.436 AIC 0.436 AIC 0.436 AIC 0.436
Average		0.0743		0.8350		0.0251		0.00046		0.3865		0.4122		7.111		16.439		0.4297
Std Dev		0.0017		0.0091		0.0013		0.00019		0.0112		0.0076		0.051		0.060		0.0126
Certified		0.074		0.835		0.025		0.0005		0.387		0.412		7.11		16.44		0.430
		2.1448		2.1098		2.1448		2.306		2.1098		2.1315		2.1098		2.1199		2.1098
C(95%)		0.0009		0.0045		0.0007		0.00014		0.0056		0.0040		0.026		0.031		0.0063
COA 192-020																		
Analysis	*	Al	*	Ca	*	Co	*	N	*	0	*	Nb	*	Sn	*	Ti	*	V
2 3 4 5 6 7 8 9 10 11 12 13 14 15 16 17 18 19 20	AA AIC AES AGA AIC TAI AES XRF AIC XRF AIC AIC AIC AIC	1.136 1.137 1.14 1.14 1.14 1.15 1.15 1.15 1.17 1.176 1.18 1.180 1.19 1.20 1.202 1.21	AGA AIC AIM AIC AES AIC AES AIC	0.0004 0.0004 0.0005 0.00061 0.0007 0.0008 0.0008 0.0008 0.0008 0.00084 0.0010	AIC AAA AIC AIC AAA AA AA AIC AGX AES XRF AES AIC AIC XRF XRF	0.096 0.0965 0.0992 0.100 0.1006 0.103 0.103 0.106 0.106 0.106 0.106 0.107 0.107 0.107	FU FU FU FU FU FU FU TN	0.0273 0.0278 0.0282 0.0287 0.0291 0.0295 0.02954 0.0298 0.0300 0.0300	FU FU FU FU FU FU FU	0.0011 0.0011 0.0014 0.00145 0.0015 0.0015 0.0016	MNA AIC AES AIC	0.1483 0.158 0.163 0.163 0.166 0.166 0.166 0.168 0.168 0.170 0.177 0.170 0.171 0.172 0.172 0.173 0.176 0.179	AAG AIH AGA AES AA AIC AES MSn AIC AES AIC AIM AIC AIC	0.0064 0.0069 0.007 0.00757 0.0078 0.008 0.008 0.008 0.0082 0.0082 0.0085 0.0085 0.0096 0.0097	XRF AIC AAA AIC AAS AIC AIC AIC AIC AIC AIC AIC AIC AIC XRF AIC XRF XRF XRF XRF	0.070 0.0709 0.071 0.072 0.0734 0.0746 0.075 0.075 0.075 0.0762 0.0764 0.0771 0.078 0.079 0.079 0.079 0.0791 0.082 0.0835	XRF XRF AIC XRF AIC MVE AIC AIC AIC AES XRF AGX AA	0.117 0.12 0.123 0.123 0.123 0.124 0.124 0.1250 0.1252 0.126 0.126 0.126 0.126 0.126 0.126 0.1270 0.129
Std Dev		0.025		0.00019		0.0046		0.00091		0.00021		0.0069		0.0009		0.0037		0.0029
Certified		1.17		0.0007		0.104		0.0290		0.0014		0.168		0.008		0.076		0.124
t		2.1199		2.2281		2.1098		2.2281		2.4469		2.1098		2.1448		2.093		2.1315
C(95%)		0.013		0.00013		0.0023		0.00061		0.00019		0.0034		0.0005		0.0018		0.0015
COA 192-020				0.0007		0.104		0.029		(0.002)		0.17		0.009		0.078		0.13
Analysis		W		As		В		Ta		×	* Met	hods of an	alysis	listed on p	age	3		
1 2 3 4 5 6 7 8	XI AI AI XI AI	IC 0.036 RF 0.044 ES 0.0459 IC 0.046 RF 0.046 IC 0.0514 RF 0.052 RF 0.071	Al Al	IC 0.005 ES 0.0051 A 0.0056 AG 0.0059	M A A A A	ES 0.0002 BD 0.0002 IC 0.0003 IC 0.0003 ES 0.0004 IC 0.0004 IC 0.0005	2 A A 1											
Average						0.0003		0.0013										
Std Dev		0.0101		0.0004			0	0.0006										
Certified						(0.0003)				Data in pare	enthes	es are not ce	rtified	but are prov	ided	for informati	on on	ly.
t		2.3646							_									
C(95%)		0.0084																
COA 192-020				(0.005)		(0.0004)		(<0.003)										

 $C(95\%) = (t \times sd)/\sqrt{n}$ The half-width confidence interval, where t is the appropriate Student's t value, sd is the interlaboratory standard deviation, and n is the number of acceptable mean values. For further information regarding the confidence interval for the certified value see ISO Guide 35:1989 section 4.

Methods of Analysis

Code	Element	Method
AA		Flame Atomic Absorption Spectrometry
AAA		Flame Atomic Absorption - standard addition method
AAG		Electro-thermal atomization (graphite furnace) Atomic Absorption Spectrometry
AES		AES - Spark Source Optical Emission Spectrometry
AGA AGX		AES - Spark Source and Glow Discharge Spectrometry average Glow Discharge and X-Ray Fluorescence Spectrometry average
AGA		AES - ICP -Inductively Coupled Plasma Spectrometry
AIH		AES - ICP - Inductively Coupled Plasma Spectrometry after hydride generation
AIM		AES - ICP Mass Spectrometry addition method
C	C, S	Combustion-Infrared Absorption (ASTM E 1019) traceable to CRMs
ECS	Cu	Sulphide precipitation, electro- deposition, gravimetric
FU	N, O	Inert gas Fusion Method (ASTM E 1019) traceable to CRMs
GMo	Mo	Gravimetry, Benzolnoxime
GNi	Ni	Dimethylglyoxime gravimetric
GSi	Si	Gravimetry with perchloric acid
IC	S	Ion chrometography
M5	Co	MAS - 5-Cl-PADAB spectrophotometric
MBD	В	MAS - Distillation separation-curcumin photometric
MCB	Cu	MAS - Bicyclohexane oxalyldihydrazone photometric
MCT MMT	Cu Mo	MAS - Tetraethylthiuram disulphide
MNA	Nb	MAS - Thiocyanate photometric MAS - Absorptionmetric determination method with 4-(2-pyridylazo)-Resorcinol
MnP	Mn	MAS - Periodate oxidation
MNR	Nb	MAS - PAR photometric
MPH	P	MAS - Hetreopoly molybdenum blue photometric
MPN	P	MAS - Butyl alcohol-trichloromethane extraction photometric
MSn	Sn	MAS - Phenylfluorone photometric
MTD	Ti	MAS - Diantipyrylmethane photometric
MVE	V	MAS - n-benzoyl phenylhydroxylamine extraction photometric
TAl	Al	EDTA titration method after seperation with cupferron
TCr	Cr	Persulfate oxidation, ferrous sulfate titrimetric
TN	N N:	Neutralization titrimetric after distillation separation
TNi	Ni	EDTA titration
XRF		X-Ray Fluorescence spectrometry

 $AES = Atomic\ Emission\ Spectrometry$

MAS = Molecular Absorption Spectrometry (photometric, spectrophotometric methods)

Co-operating Laboratories: The co-operating laboratories were:

Laboratory
Allvac, Lockport, New York
Allvac, Monroe, North Carolina
ANAREM, Prague, Czech Republic
Brammer Standard Co., Inc., Houston, Texas
China National Analysis Center for Iron and Steel, Beijing, China
Crucible Specialty Steel, Syracuse, New York
J. Dirats and Co., Inc., Westfield, Massachusetts
IncoTest, Huntington, West Virginia
LECO Corporation, St. Joseph, Michigan
Shiva Analyticals (India) Ltd., Hoskote, Bangalore, India
VHG Laboratories, Inc., Manchester, New Hampshire

Thomas Herdlein
Patrick M. Cole
Karel Bičovský
Richard P. Beaumont
Prof. Wang Haizhou
William Mastroe
Eric E. Dirats
Melissa G. Staley
Dennis Lawrenz
Dr. T. V. Ramakrishna
Julie M. McIntosh

Laboratory contact

Additional analytical data: This material was used as an unknown test specimen number 0012 in a nationally recognized Proficiency Testing Program (PTP) for stainless steel. Most of the participating laboratories used one or more of the ASTM Standard Test Methods E 572, E 1019, and E 1086. The PTP data was not used in calculating the certified values listed on pages 1 and 2. The data shown below are the results from the PTP.

Combustion Instrument Analysis using ASTM Standard Test Method E 1019

	С	S	N	О
Number of Labs	20	14	16	13
Grand Average	0.0743	0.0004	0.0293	0.0017
Standard Deviation	0.0032	0.0002	0.0011	0.0007

Optical Emission Spectrometric Analysis using ASTM Standard Test Method E 1086

	C	Mn	P	S	Si	Cu	Ni	N*
Number of Labs	10	13	13	11	13	12	10	4
Grand Average	0.0772	0.8185	0.0242	0.0017	0.3800	0.4111	7.0796	0.0315
Standard Deviation	0.0044	0.0152	0.0017	0.0014	0.0189	0.0111	0.0778	0.0021
	Cr	Mo	Co*	V*	Nb*	Sn*	Ti*	Al*
Number of Labs	11	13	8	8	8	6	8	7
Grand Average	16.4291	0.4361	0.1076	0.1192	0.1717	0.0085	0.0732	1.2464
Standard Deviation	0.1358	0.0191	0.0042	0.0076	0.0082	0.0017	0.0052	0.1121

X-ray Emission Spectrometric Analysis using ASTM Standard Test Method E 572

	Mn	P*	Si*	Cu	Ni	Cr	Mo
Number of Labs	14	9	8	13	13	14	12
Grand Average	0.8175	0.0249	0.3863	0.4098	7.0883	16.3884	0.4274
Standard Deviation	0.0160	0.0011	0.0100	0.0103	0.0424	0.0999	0.0083
	V*	Co	Nb	Sn*	Ti*	Al*	
Number of Labs	9	13	7	7	5	6	
Grand Average	0.1250	0.1081	0.1688	0.0084	0.0748	1.1747	
Standard Deviation	0.0068	0.0065	0.0041	0.0020	0.0032	0.1058	

^{*} The elements are not listed in the Scope of the ASTM Standard Test Method but are reported for information.

Certification Process: The requirements of ISO Guide 31, ISO Guide 34, ISO Guide 35, and ASTM Standard Guides E 1724 and E 1831 were followed for the preparation of this reference material and certificate of analysis. This is a Certified Reference Material as defined by ISO Guide 30.

Analysis: Chemical analyses were made on chips prepared by a lathe from the certified portion of the discs in accordance with ASTM Standard Practice E 1806. The laboratories participating in the testing normally followed the requirements of ISO Guide 25 and/or ISO Standard 17025. Individual values listed on page 2 are the average of each analyst's results. Methods of analysis are listed on page 3.

Outliers: Some outlying data was excluded from the data listed on page 2 due to technical assessment of the cooperating laboratories and statistical evaluation.

Traceability: The following Certified Reference Materials were used to validate the analytical data listed on page 2: SRM 15h, 32b, 101g, 121d, 123c, 126c, 133b, 160b, 343a, 344, 345, 346a, 348a, 361, 864, 865, 868, 2171; ECRM 096-1, 284-1, 286-1, 289-1, 295-1; BCS 342, 351, 466/1, 467/1, 475; BAM 230-1.

Homogeneity: This Certified Reference Material was tested for homogeneity using ASTM Standard Method E 826 and found acceptable. It was also examined by optical emission spectrometry using ASTM Standard Test Method E 1086 and found to be compatible with the following Reference Materials: SRM C1151, C1152, C1153; BS CA304-2, 81G, 85D, 184, 184A.

Validity statement: ISO Guide 31 states that the certification should contain an expiration date for all materials where instability has been demonstrated or is considered possible, after which the certified value is no longer guaranteed by the certifying body. Whereas this material is in a solid form and stable, no expiration date is specified.

Source: This material was produced by AL Tech Specialty Steel Corporation, Dunkirk, New York. It was melted by an electric arc furnace, bottom poured into ingots, hot rolled, and finished with a normalized heat treatment.

Form: This Certified Reference Material is in the form of a disc, approximately 38 mm in diameter and 12 mm thick.

Use: This Certified Reference Material is intended for use in optical emission and x-ray spectrometric methods of analysis. Refer to ISO Guide 33 for information about the use of Reference Materials.

Certified area: The entire depth of the disc may be used.

Caution: As with any bar material, avoid optical emission spectrometric burns in the center of the disc (5 mm radius), as some segregation may be present.

Sample Preparation: For best analytical results, use the same method for preparing the analytical surface on all reference materials as you use for production specimens. Avoid overheating the disc during surface preparation.

Certificate Number: The unique identification number for this certificate of analysis is 192REV-032901-px, where x indicates the page number. Refer to future Brammer Standard Company catalogs for information on any revisions to this or other Brammer Standard reference materials. You may also obtain information on revisions of certificates from the internet at brammerstandard.com.

Revision information: A new interlaboratory testing program (ITP) was initiated for this material when a replacement was tested. There was no dramatic change in analysis originally certified. The original values certified on February 1, 1995, are listed on page 2 at the bottom of each table.

Safety Notice: A Material Safety Data Sheet (MSDS) is not required for this material. This material will not release or otherwise result in exposure to a hazardous chemical under normal conditions of use. Inquiries concerning this Reference Material should be directed to:

Brammer Standa 14603 Benfer Ro	,	Phon	e: (281) 440-9396	web	brammerstandard.com
Houston, Texas	77069-2895	USA Fax:	(281) 440-4432	e-mail	bramstan@netropolis.net
Certified by:	G. R. Bramm	er	on March 29, 2001		

Brammer Standard Company, Inc., is accredited to ISO Guide 34 as a Reference Material Producer for the production of Certified Reference Materials and Reference Materials by A2LA (Certificate Number 656.02) The scope of accreditation is listed on the website: www.brammerstandard.com

By Certificate Number 10539, the Quality System of Brammer Standard Company, Inc., is registered to ISO 9002:1994 by National Quality Assurance, U.S.A.

Brammer Standard Company's Chemical Laboratory is accredited to ISO Guide 25 by A2LA. (Certificate Number 656.01)

References:

ASTM documents available from ASTM, 100 Barr Harbor Drive, West Conshohocken, PA 19428-2959, Telephone: 610-832-9500 Fax: 610-832-9555 e-mail: service@astm.org Website: www.astm.org

E 572 - 94 Standard Test Method for X-Ray Emissioin Spectrometric Analysis of Stainless Steel

E 826 - 85 (Reapproved 1996) Standard Practice for Testing Homogeneity of Materials for the Development of Reference Materials

E 1019 - 2000 Standard Test Methods for Determination of Carbon, Sulfur, Nitrogen, and Oxygen in Steel and in Iron, Nickel, and Cobalt Alloys

E 1086 - 94 Standard Test Method for Optical Emission Vacuum Spectrometric Analysis of Stainless Steel by the Point-to-Plane Excitation Technique

E 1724 - 95 Standard Guide for Testing and Certification of Metal and Metal-Related Reference Materials

E 1806 - 96 Standard Practice for Sampling Steel and Iron for Determination of Chemical Composition

E 1831 - 96 Standard Guide for Preparing Certificates for Reference Materials Relating to Chemical Composition of Metals, Ores, and Related Materials.

ISO Guides available from Global Engineering - www.global.ihs.com

ISO Standard 17025 (First edition, 1999), General requirements for the competence of calibration and testing laboratories.

ISO Guide 25 (Third edition, 1990), General requirements for the competence of calibration and testing laboratories.

ISO Guide 30 (Second edition, 1991), Terms and definitions used in connection with reference materials.

ISO Guide 31 (Second edition, 2000), Reference materials -Contents of certificates and labels.

ISO Guide 33 (Second edition, 2000), Uses of certified reference materials.

ISO Guide 34 (Second edition, 2000), General requirements for the competence of reference material producers.

ISO Guide 35 (Second edition, 1989), Certification of reference materials - General and statistical principles.

Other useful documents available from NIST, U.S. Department of Commerce, Gaithersburg, MD 20899.

NIST Special Publication 260-100, Handbook for SRM Users

NIST Special Publication 829, Use of NIST Standard Reference Materials for Decisions on Performance of Analytical Chemical Methods and Laboratories